Optech Solutions Optech Solutions

The ISO 9001:2008 international quality certification system is adopted by our company

TO BE A WORLD-LEADING ANALYTICAL TESTING SOLUTIONS PROVIDER

Spectroscopy

Chromatography

Mass Spectrometry



EDX1800B

X-ray Fluorescence Spectrometer

| Full-elemant Analysis for minerals | Plating Thickness Testing | Precious Metals Testing

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Test data in this manual, if not noted, is our

company's test data.

All information in this manual is for reference only, which is subject to any change without notice.

Skyray Instrument Copyright 2010 Press date:2011.07.05

Instrument Introduction:

With the widespread of EDX1800B over different fields, we design this type to meet the need of optimizing the product performance and improve the safety protection grade.

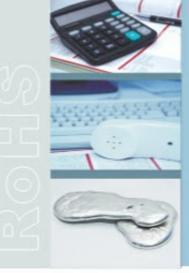
The reliability of the product is improved by using the high voltage source and X-ray tube of the new generation and the testing efficiency is improved by the adopting the high power of X-ray tube.



Testing 75 kinds of elements, 1ppm limit of detection, Repeatability 0.1%, Stability 0.1%







Application fields:

- RoHS testing
- Mining and alloy (Cu, stainless steel and so on) componential analysis
- Measurement of plating thickness, measurement of electroplate liquid and plating content
- The content test of precious metal such as gold, platinum and silver and different kinds of jewelry
- Mainly applied in RoHS directive industries, precious metals and jewelries processing industries banks, jewelry shops and test institutes; electroplating industries

Good shielding action of X-ray tube of new generation, radiation level of X-ray is equal to that of common atmospheric environment

The performance is stable and reliable, achieving higher test efficiency

The automatic function of door sensor and high voltage lock gives you protection from all directions

Performance advantages:

Down-side X-ray Source: meet the test requirements of samples of different kinds and shapes

Collimator and filter: the Auto-switch between various collimators and filters to meet the application of different testing methods

Movable platform: sophisticated manual movable platform is convenient for locating test point

High-resolution detector: improve the analyzing accuracy

High voltage source and X-ray tube of the new generation: the performance is stable and reliable, achieving higher test efficiency

Technical specifications:

Measurable elements: S to U.

Limit of detection (LOD) reaches 1ppm.

Element content: ppm to 99.99%

Arbitrary optional analysis and identification models

Independent matrix effect correction models

Multi-variable non-linear regression procedure

Excellent repeatability: 0.1% Long-time working stability: 0.1%

Ambient temperature: 15℃ to 30℃

Power supply: AC 220V±5V, AC purified stabilized voltage power supply.

Energy resolution: 160±5eV

Sample chamber size: 439mm×300mm×50mm Instrument size: 550mm×410mm×320mm

Instrument weight: 45kg

Standard configurations:

Movable sample platform
Signal-to-Noise Enhancer (SNE)
Electric-cooling Si-PIN detector
Signal detection electronic circuit
High and low voltage power
X-ray tube of high power
Computer and ink-jet printer

Streamlined man-machine design, promising your operation security

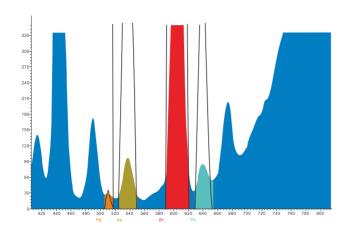
Operation indicator makes you operate comfortably



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Test cases:





RoHS Testing

Test Results Spectrum

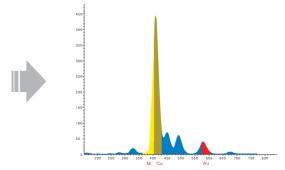




Mining Testing

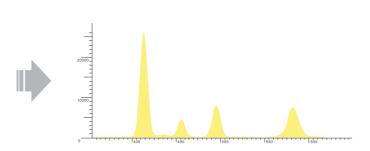


Plating Thickness Testing





Precious Metals Testing



What are RoHS and WEEE Directives?

The European Union has adopted Directive 2002/95/EC on the restriction of certain hazardous substances (RoHS) and Directive 2002/95/EC on waste electrical and electronic equipment (WEEE) with their publication in the Official Journal of the European Union on February 13, 2003. WEEE comes into effect on August 13, 2005 and RoHS requires the substitution of various heavy metals (lead, mercury, cadmium and hexavalent chromium) and brominated flame retardants (polybrominated biphenyls [PBB] or polybrominated diphenyl ethers [PBDE]) in new electrical and electronic equipment put on the market from July 1, 2006.

Testing standard of substances restricted by RoHS Directive

Hazardous substances	Standards (mg/kg)					
Cd	100					
Pb	1000					
Hg	1000					
Cr ⁶⁺	1000					
PBBs	1000					
PBDEs	1000					

Restricted substances and their typical uses

Pb	
Solders	
Paints	Pigments and driers
Glass materials	Pb is allowed in fluorescent lamp
Ceramic materials	Pb is allowed in certain electronic ceramic materials
Iron, aluminum and copper materials	A certain amount of Pb is allowed
Plastics	PVC stabilizer and pigments
Batteries	Pb is allowed in acidic batteries for vehicles

Cd	
Plastics	Stabilizer and pigments
Solders	Seldom used
Ceramics	Seldom used
Connectors	Relays and switches
Batteries	Cd is allowed in Ni-Cd batteries
Semiconductors	Optical sensors and solar cell panels

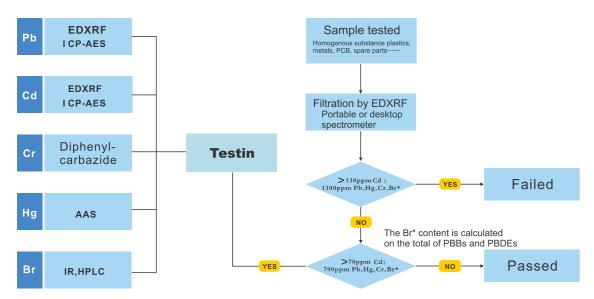
Hg	
Batteries	Prohibited (see battery directive)
Connectors	Relays and sensitive switches
Fluorescent lamps	A certain amount of Hg is allowed

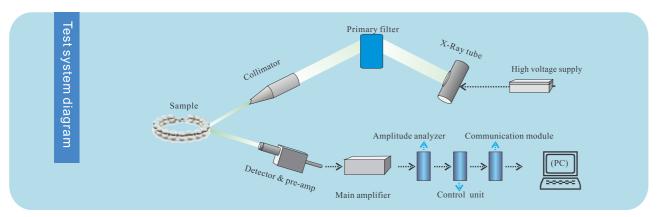
Cr ⁶⁺	
Passivation layers	Commonly used for naked metal surfaces to enhance adhesion of plating layers
Anti-corrosive plating layers	Painting and plating layers
Chrome plating layers	Plating layer of chromium metal is not under control
Plasticizer	Commonly used to plastics plating process but not final products

PBBs & PBDEs	
Plastics	Brominated flame retardants

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The analytical method of filtration for XRF to test RoHS substances





Characteristic X-radiation of element

Each element will emit X-ray at its own energy level when excited. This X-ray is characteristic and called X-ray fluorescence. It is the foundation of analysis.

Scattering

It is the background of spectrum.

Photoelement

The photoelectron is the foundation of detector. In the sample, the X-ray intensity of every element is expressed as I1,I2,I3,I4,I5 ······ respectively. The element content C is the function of X-ray fluorescence intensity I, expressed as follows:

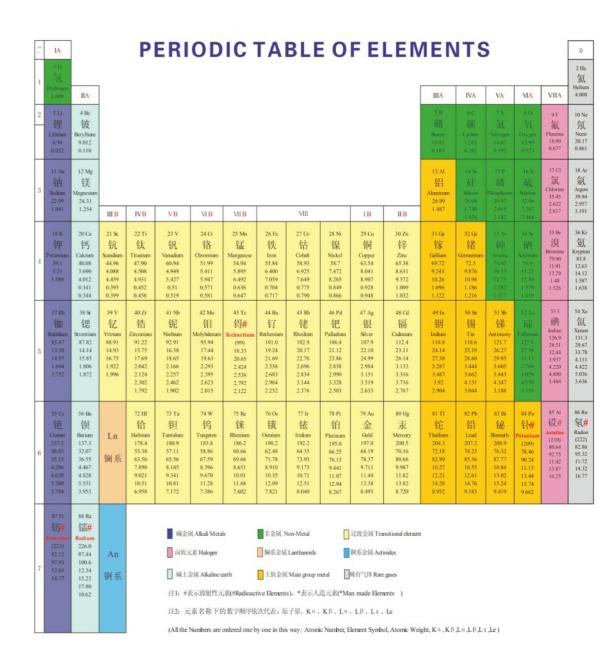
$$C = f(I_1, I_2, I_3, I_4, I_5 \cdots)$$

This equation is too complicated and can be simplified as:

$$C=K_1I_1+K_2I_2+K_3I_3+K_4I_4+K_5I_5$$
....

Where

C is the element content in the sample; I1,I2,I3,I4,I5 ······· are X-ray intensity of element respectively; K1,K2, K3,K4,K5 ····· are coefficients which can be determined by measuring known standard sample to calibrate.



Ln 镧系	57 La Lanthanun 138.9 33.30 37.99 4.651 5.043 5.789 4.124	58 Ce Tili Cerium 140.1 34.57 39.45 4.840 5.262 6.052 4.287	59 Pr \$10 110 Prascody mism 140.9 35.86 40.95 5.034 5.489 6.322 4.452	60 Nd EX Neodymium 144.2 37.19 42.48 5.230 5.722 6.602 4.632	61 Pm \$\frac{1}{12}\frac{1}{1	62 Sm Sumarium 150.4 39.91 45.65 5.636 6.206 7.180 4.994	63 Eu Europium 152.0 41.32 47.28 5.846 6.456 7.478 5.176	64 Gd Gadolinium 157.2 42.76 48.95 6.059 6.714 7.778 5.361	65 Tb 100 Terbium 158.9 44.23 50.65 6.275 6.979 8.104 5.546	66 Dy 前 Dysprosium 162.5 45.73 52.38 6.495 7.249 8.418 5.742	67 Ho Holmium 164.9 47.26 54.16 6.720 7.528 8.748 5.942	68 Er \$\frac{\pmathrm{4E}}{\pmathrm{167.2}}\$ 48.82 55.96 6.948 7.810 9.089 6.152	69 Tm
An 何系	89 Ac Actinium (227) 89.79 103.3 12.65 15.71 18.41	90 Th ## Thorium (232) 92.19 106.1 12.97 16.2 18.98 11.12	91 Pa ‡‡ Protactinium 231.0 94.64 108.9 13.29 16.7 19.55 11.36	92 U 抽# Uranium 238.0 97.14 111.8 13.61 17.22 20.16 11.62	93 Np 全章 # Neptunium (237) 99.69 114.7 13.95 17.74 20.77 11.89	94 Pu ## Plutonium (244) 102.3 117.7 14.28 18.28 21.40 12.12	95Am 401# *Americium (243) 104.9 120.8 14.62 18.83 22.04 12.38	96 Cm [ii] # * Curium (247) 107.7 123.9 14.96 19.39 22.69	97 Bk 管計 *Berkelium (247) 110.5 127.1 15.31 19.97 23.37	98 Cf ## *C alifornium (251) 113.3 130.4 15.66 20.56 24.06	99 Es 袋# *Einsteinium (252) 116.2 133.7 16.02 21.17 24.76	100 Fm 设# *Fermium (257) 119.2 137.2 16.38 21.79 25.47	

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